12500 TI Boulevard, MS 8640, Dallas, Texas 75243

PCN#20230327003.1
Qualification of new Fab site (RFAB) using qualified Process Technology, Die Revision, and additional Assembly & BOM option for select devices

Change Notification / Sample Request

Date: March 30, 2023
To: TOKYO ELECTRON DEVICE (DSTR) PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments (TI). The details of this change are on the following pages, and are in alignment with our standard product change notification (PCN) process.

TI requires acknowledgement of receipt of this notification within 30 days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If samples or additional data are required, requests must be received within 30 days of this notification, given that samples are not built ahead of the change.

The Proposed First Ship date in this PCN letter is the earliest possible date that customers could receive the changed material. It is our commitment that the changed device will not ship before that date. If samples are requested within the 30 day sample request window, customers will still have 30-days to complete their evaluation regardless of the proposed 1st ship date.

This particular PCN is related to TI's multiyear transition plan for our two remaining factories with 150-millimeter production (DFAB in Dallas, Texas, and SFAB in Sherman, Texas). DFAB will remain open, but will focus on 200-mm production, with a smaller set of technologies. SFAB will close no earlier than 2024 and no later than 2025. As referenced in the "reason for change" below, these changes are part of our multiyear plan to transition these products to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

For questions regarding this notice or to provide acknowledgement of this PCN, you may contact your local Field Sales Representative or the PCN Team (PCN_ww_admin_team@list.ti.com). For sample requests or sample related questions, contact your local Field Sales Representative. As always, we thank you for your continued business.

PCN Team
SC Business Services

20230327003.1
Attachment: 1

Products Affected:

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

DEVICE	CUSTOMER PART NUMBER
SN74LV174APWR	null
SN74LV06ANSR	null
SN74LV06APWR	null
SN74LV166APWR	null
SN74LV393APWR	null
SN74LV541APWR	null
SN74LV540APWR	null
SN74LV541ADBR	null
SN74LV541APWRG4	null
SN74LV573APWR	null
SN74LV05APWR	null
SN74LV175APWR	null
SN74LV244ADBR	null
SN74LV367APWR	null
SN74LV10APWR	null
SN74LV165ADRG4	null

Technical details of this Product Change follow on the next page(s).

PCN Number:	20230327003.1	PCN Date:	March 30, 2023
Title:	Qualification of new Fab site (RFAB) using qualified Process Technology, Die Revision, and additional Assembly & BOM options for select devices		
Customer Contact:	PCN Manager	Dept:	Quality Services
Proposed 1st Ship Date:	Jun 27, 2023	Sample requests accepted until:	Apr 29, 2023*

***Sample requests received after April 29, 2023 will not be supported.**

Change Type:					
☒	Assembly Site	☒	Assembly Process	☒	Assembly Materials
☒	Design	☒	Electrical Specification	☐	Mechanical Specification
☐	Test Site	☐	Packing/Shipping/Labeling	☐	Test Process
☐	Wafer Bump Site	☐	Wafer Bump Material	☐	Wafer Bump Process
☒	Wafer Fab Site	☒	Wafer Fab Materials	☒	Wafer Fab Process
		☐	Part number change		

PCN Details

Description of Change:

Texas Instruments is pleased to announce the qualification of a new fab & process technology (RFAB, LBC9) and Assembly & BOM option for selected devices as listed below in the product affected section. Construction differences are noted below:

Current Fab Site			Additional Fab Site		
Current Fab Site	**Process**	**Wafer Diameter**	**Additional Fab Site**	**Process**	**Wafer Diameter**
SFAB	HCMOS	150 mm	RFAB	LBC9	300 mm

The die was also changed as a result of the process change.

Additionally, there will be a BOM/Assembly options introduced for these devices:

Group 1 Device list (RFAB/Process migration & TFME as new Assembly and BOM options– PW packaged devices)

	MLA (Current)	MLA (New)	TFME
Bond wire diameter (Cu)	0.96 mil	0.8mil	0.8 mil
Lead finish	NiPdAu	NiPdAu	Matte Sn
Mount Compound	4147858	4147858	SID#A-03
Mold Compound	4211471	4211471	SID#R-31

Group 2 Device list (RFAB/Process migration & HFTF as new Assembly and BOM options – D Packaged Device)

	MLA (Current)	MLA (New)	HFTF
Bond wire diameter (Cu)	0.96 mil	0.8mil	0.8 mil
Lead finish	NiPdAu	NiPdAu	Matte Sn
Mount Compound	4147858	4147858	SID#R-03
Mold Compound	4211880	4211880	SID#R-30

Group 3 Device list (RFAB/Process migration & BOM Option – PW, NS, DW & DB

packaged devices)

	MLA Current	MLA New
Bond wire diameter (Cu)	0.96 mil	0.8 mil

Group 4 Device list (RFAB/Process migration & FMX as new Assembly and BOM options– D packaged devices)

	MLA (Current)	MLA (New)	FMX
Bond wire diameter (Cu)	0.96 mil	0.8mil	0.8 mil

Group 5 Device list (RFAB/Process migration & MLA as new Assembly and BOM options – D packaged devices)

	ASESH	FMX Current	FMX (New)	MLA (New)
Bond wire diameter (Cu)	0.8 mil	0.96 mil	0.8mil	0.8 mil
Lead finish	Matte Sn	NiPdAu	NiPdAu	NiPdAu
Mount Compound	SID#EY1000063	4147858	4147858	4147858
Mold Compound	SID#EN2000506	4211880	4211880	4211880

Upon expiry of this PCN TI will combine lead free solutions in a single ***standard part number***, for the devices in groups 1 & 2. For example; ***SN74LV10APWR*** – can ship with both Matte Sn and NiPdAu/Ag.

Example:

- Customer order for 7500 units of SN74LV10APWR with 2500 units SPQ (Standard Pack Quantity per Reel).

- TI can satisfy the above order in one of the following ways.
  - I. 3 Reels of NiPdAu finish.
  - II. 3 Reels of Matte Sn finish
  - III. 2 Reels of Matte Sn and 1 reel of NiPdAu finish.
  - IV. 2 Reels of NiPdAu and 1 reel of Matte Sn finish.

Additionally, as a result of these changes, some of the impacted device datasheets will be updated. Target for these datasheet updates is the start of production. For a preview of these upcoming datasheet changes, please see below:

Reason for Change:

These changes are part of our multiyear plan to transition products from our 150-millimeter factories to newer, more efficient manufacturing processes and technologies, underscoring our commitment to product longevity and supply continuity.

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

RoHS	REACH	Green Status	IEC 62474
☒ No Change	☒ No Change	☒ No Change	☒ No Change

Changes to product identification resulting from this PCN:

Fab Site Information:

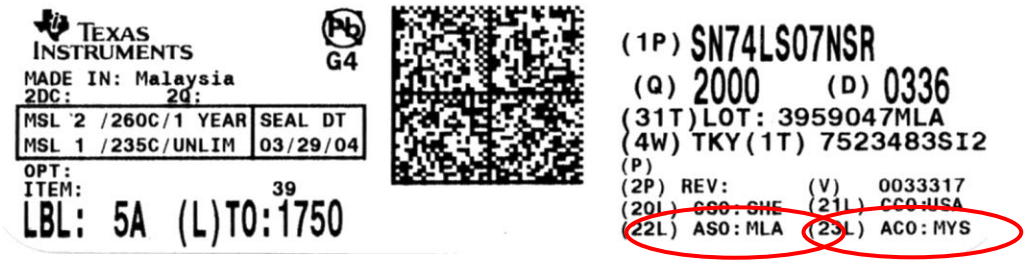
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City
SH-BIP-1	SHE	USA	Sherman
RFAB	**RFB**	**USA**	**Richardson**

Die Rev:

Current	**New**
Die Rev [2P]	**Die Rev [2P]**
H, I, M	**A**

Assembly Site	Assembly Site Origin (22L)	Assembly Country Code (23L)	Assembly City
MLA	MLA	MYS	Kuala Lumpur
ASESH	ASH	CHN	Shanghai
FMX	MEX	MEX	Aguascalientes
HFTFAT	**HFT**	**CHN**	**Hefei**
TFME	**NFM**	**CHN**	**Economic Development Zone**

Sample product shipping label (not actual product label)



Product Affected:

Group 1 Device list (RFAB/Process migration & TFME as new Assembly and BOM options– PW packaged devices)

SN74LV05APWR	SN74LV10APWR	SN74LV174APWR	SN74LV367APWR
SN74LV06APWR	SN74LV166APWR	SN74LV175APWR	SN74LV393APWR

Group 2 Device list (RFAB/Process migration & HFTF as new Assembly and BOM options – D Packaged Device)

SN74LV06ADR

Group 3 Device list (RFAB/Process migration & BOM Option – PW, NS, DW & DB packaged devices)

SN74LV06ANSR	SN74LV244ADWRG4	SN74LV374ADWR	SN74LV541APWR
SN74LV244ADBR	SN74LV273ADBR	SN74LV540APWR	SN74LV541APWRG4
SN74LV244ADBRE4	SN74LV273ADBRE4	SN74LV541ADBR	SN74LV573APWR
SN74LV244ADBRG4	SN74LV273ADBRG4	SN74LV541ADBRE4	SN74LV573APWRG4
SN74LV244ADWR	SN74LV273ADWR	SN74LV541ADWR	

Group 4 Device list (RFAB/Process migration & FMX as new Assembly and BOM options– D packaged devices)

SN74LV164ADR	SN74LV393ADR

Group 5 Device list (RFAB/Process migration & MLA as new Assembly and BOM options – D packaged devices)

SN74LV138ADR	SN74LV165ADR	SN74LV174ADR	SN74LV595ADR
SN74LV157ADR	SN74LV165ADRG4	SN74LV367ADR	

For alternate parts with similar or improved performance, please visit the product page on TI.com"

Qualification Report
Approve Date 15-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV573APWR	Qual Device: SN74LV540APWR	QBS Reference: SN74HCS244QPWRQ1	QBS Reference: SN74LV244AQWRKSRQ1	QBS Reference: SN74LV240APWR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	1/77/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	1/77/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	1/77
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	1/45/0	1/45/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	1/77/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	-	-	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	1/3/0	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	1/3/0	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	1/6/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-

- QBS: Qual By Similarity
- Qual Device SN74LV573APWR is qualified at MSL1 260C
- Qual Device SN74LV540APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2210-016

Qualification Report
Approve Date 16-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV244ADWR	Qual Device: SN74LV273ADWR	Qual Device: SN74LV374ADWR	Qual Device: SN74LV541ADWR	QBS Reference: SN74HCS244QPWRQ1	QBS Reference: SN74LV244AQWRKSRQ1	QBS Reference: SN74LV240APWR	QBS Reference: SN74LV374APWR	QBS Referen SN74LV574AP
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	1/77/0	1/77/0	-	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	3/231/0	1/77/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	1/77/0	1/77/0	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	1/45/0	1/45/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	1/77/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/77/0	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	1/3/0	1/3/0	-	-	1/3/0	1/3/0	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	1/3/0	1/3/0	-	-	-
ESD	E2	ESD HBM	-	1000 Volts	-	-	-	-	-	-	1/3/0	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	1/3/0	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	1/3/0	1/3/0	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	1/6/0	1/6/0	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	-	-	1/30/0	1/30/0	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	-	3/90/0	3/90/0	-	-	-

- QBS: Qual By Similarity
- Qual Device SN74LV244ADWR is qualified at MSL1 260C
- Qual Device SN74LV273ADWR is qualified at MSL1 260C
- Qual Device SN74LV374ADWR is qualified at MSL1 260C
- Qual Device SN74LV541ADWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2210-017

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV244ADBR	Qual Device: SN74LV273ADBR	Qual Device: SN74LV541ADBR	QBS Reference: SN74HCS244QPWRQ1	QBS Reference: TL494IDR	QBS Reference: TLC320AD77CDBR	QBS Reference: SN74LV244AQWRKSRQ1	QBS Reference: SN74LV273AQWRKSRQ1	QBS Reference: SN74LV541AQWRKSRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	1/77/0	-	-	1/77/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-	1/77/0	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	1/77/0	-	-	1/77/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	3/231/0	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	1/45/0	-	-	1/45/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	1/77/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	1/77/0	-	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	-	-	-	1/10/0	1/10/0
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	-	-	-	1/3/0	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	-	-	1/3/0	-	-
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	-	-	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0	-	-	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	-	-	1/6/0	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	-	-	-	-	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	3/90/0	-	-	3/90/0	1/30/0	1/30/0

- QBS: Qual By Similarity
- Qual Device SN74LV244ADBR is qualified at MSL1 260C

- Qual Device SN74LV273ADBR is qualified at MSL1 260C
- Qual Device SN74LV541ADBR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2210-018

Qualification Report
Approve Date 15-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV541APWR	Qual Device: SN74LV541APWRG4	QBS Reference: SN74HCS244QPWRQ1	QBS Reference: SN74LV244AQWRKSRQ1	QBS Reference: SN74LV240APWR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	1/77/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	1/77/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	1/77/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	1/45/0	1/45/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	1/77/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	1/3/0
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	1/3/0	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	1/3/0	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	1/6/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-

- QBS: Qual By Similarity
- Qual Device SN74LV541APWR is qualified at MSL1 260C
- Qual Device SN74LV541APWRG4 is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2212-003

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV175APWR	Qual Device: SN74LV166APWR	Qual Device: SN74LV174APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74HCS74PWR	QBS Reference: SN74LV138APWR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	3/231/0	1/77	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/231/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	3/135/0	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	3/231/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	3/2400/0	-	-	-

SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;	-	-	-	-	-	3/66/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder;	-	-	-	-	-	3/66/0	-	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	-	-	-	3/15/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	3/30/0	-	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	-	-	3/9/0	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	-	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	3/90/0	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	3/90/0	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV175APWR is qualified at MSL1 260C
- Qual Device SN74LV166APWR is qualified at MSL1 260C
- Qual Device SN74LV174APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2212-036

TI Information
Selective Disclosure

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV393APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74HCS74PWR	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/231/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	-	-	-

HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;	-	-	-	3/66/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder;	-	-	-	3/66/0	-	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	-	3/15/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0	-	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	3/9/0	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	1/3/0	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	1/3/0	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	1/6/0	-	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	3/90/0	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	3/90/0	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV393APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2212-037

Qualification Report
Approve Date 20-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV166APWR	Qual Device: SN74LV174APWR	Qual Device: SN74LV175APWR	QBS Reference: TMUX1308QPWRQ1	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	3/231/0	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	3/231/0	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/135/0	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	3/231/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	3/231/0	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	3/2400/0	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	1/15/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	1/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	3/30/0	3/30/0	-
ESD	E2	ESD CDM	-	2000 Volts	-	-	-	1/3/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	-	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	5000 Volts	-	-	-	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	-	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	3/90/0	3/90/0	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV166APWR is qualified at MSL1 260C
- Qual Device SN74LV174APWR is qualified at MSL1 260C
- Qual Device SN74LV175APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2212-038

Qualification Report
Approve Date 21-SEPTEMBER-2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV4T125PWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74HCS74PWR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	1/77/0	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77/0	3/231/0	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	3/231/0
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	3/30/0	3/15/0
ESD	E2	ESD CDM	-	1500 Volts	1/3/0	1/3/0	3/9/0
ESD	E2	ESD HBM	-	4000 Volts	-	1/3/0	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	-	3/90/0	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV00APWR is qualified at MSL1 260C
- Qual Device SN74LV04APWR is qualified at MSL1 260C
- Qual Device SN74LV02APWR is qualified at MSL1 260C
- Qual Device SN74LV05APWR is qualified at MSL1 260C
- Qual Device SN74LV06APWR is qualified at MSL1 260C
- Qual Device SN74LV07APWR is qualified at MSL1 260C
- Qual Device SN74LV07APWRG3 is qualified at MSL1 260C
- Qual Device SN74LV08APWR is qualified at MSL1 260C
- Qual Device SN74LV10APWR is qualified at MSL1 260C
- Qual Device SN74LV11APWR is qualified at MSL1 260C
- Qual Device SN74LV125APWR is qualified at MSL1 260C
- Qual Device SN74LV126APWR is qualified at MSL1 260C
- Qual Device SN74LV132APWR is qualified at MSL1 260C
- Qual Device SN74LV14APWR is qualified at MSL1 260C
- Qual Device SN74LV20APWR is qualified at MSL1 260C
- Qual Device SN74LV21APWR is qualified at MSL1 260C
- Qual Device SN74LV27APWR is qualified at MSL1 260C
- Qual Device SN74LV32APWR is qualified at MSL1 260C
- Qual Device SN74LV74APWR is qualified at MSL1 260C
- Qual Device SN74LV86APWR is qualified at MSL1 260C
- Qual Device SN74LV4T125PWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2111-095

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV164ADR	Qual Device: SN74LV393ADR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74HCS74QDRQ1	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV164ADR	QBS Reference: SN74LV393ADR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	3/231/0	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	-	-	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	3/231/0	-	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	3/135/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-	-	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	3/45/0	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	3/45/0	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	3/30/0	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	-	-	1/3/0	1/3/0	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	1/6/0	-	-	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	1/30/0	1/30/0	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV164ADR is qualified at MSL1 260C
- Qual Device SN74LV393ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-012

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV164APWR	Qual Device: SN74LV393APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV164APWR is qualified at MSL1 260C
- Qual Device SN74LV393APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-016

Qualification Report
Approve Date 17-March-2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV138ADR	Qual Device: SN74LV157ADR	Qual Device: SN74LV165ADR	Qual Device: SN74LV165ADRG4	Qual Device: SN74LV174ADR	Qual Device: SN74LV367ADR	Qual Device: SN74LV595ADR	QBS Reference: SN74HCS74QDRQ1	QBS Reference: SN74HCS74QDRQ1	QBS Reference: SN74LV138ADR	QBS Reference: SN74LV157ADR	QBS Reference: SN74LV595ADR	QBS Reference: SN74LV595AQDRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	3/231/0	3/231/0	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	3/231/0	-	-	-	-	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	-	-	-	3/231/0	3/231/0	-	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	-	3/135/0	3/135/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	-	3/231/0	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	-	-	-	3/2400/0	-	-	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	1/15/0	3/45/0	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	1/15/0	3/45/0	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	-	-	-	3/30/0	3/30/0	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	-	-	-	-	-	-	-	1/3/0	1/3/0	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	-	-	-	1/3/0	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	-	-	-	1/3/0	1/3/0	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	-	1/6/0	1/6/0	-	-	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	-	-	1/30/0	1/30/0	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	-	-	-	-	3/90/0	3/90/0	-	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV138ADR is qualified at MSL1 260C
- Qual Device SN74LV157ADR is qualified at MSL1 260C
- Qual Device SN74LV165ADR is qualified at MSL1 260C
- Qual Device SN74LV165ADRG4 is qualified at MSL1 260C
- Qual Device SN74LV174ADR is qualified at MSL1 260C
- Qual Device SN74LV367ADR is qualified at MSL1 260C
- Qual Device SN74LV595ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -65C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TIs external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-020

Qualification Report
Approve Date 16-NOVEMBER -2022

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV138APWR	Qual Device: SN74LV138APWR	Qual Device: SN74LV157APWR	Qual Device: SN74LV161APWR	Qual Device: SN74LV165APWR	Qual Device: SN74LV165APWR	Qual Device: SN74LV165APWRG3	Qual Device: SN74LV367APWR	Qual Device: SN74LV595APWR	Qual Device: SN74LV595APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74HCS74QPWR	QBS Reference: SN74LV595AQPWRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	3/231/0	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	3/231/0	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	1/77	-	-	-	-	-	-	-	-	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	-	-	-	-	-	-	3/231/0	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	-	-	-	-	-	3/231/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	-	-	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	-	-	-	-	3/231/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	-	-	-	-	-	-	3/2400/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	-	-	-	1/15/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;	-	-	-	-	-	-	-	-	-	-	-	-	3/66/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	-	-	-	1/15/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder;	-	-	-	-	-	-	-	-	-	-	-	-	3/66/0	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	-	-	-	-	-	-	-	-	-	-	3/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	-	-	-	-	-	-	3/30/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	-	-	-	1/3/0	-	1/3/0	-	3/9/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	-	-	-	-	-	-	1/3/0	-	1/3/0

ESD	E2	ESD HBM	-	1000 Volts	-	-	-	-	-	-	-	1/3/0	-	-	-	-	-
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	-	-	-	-	-	-	1/3/0	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	-	1/3/0	-	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	-	-	-	-	1/6/0	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	-	3/90/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	-	-	-	-	-	-	-	3/90/0	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV138APWR is qualified at MSL1 260C
- Qual Device SN74LV139APWR is qualified at MSL1 260C
- Qual Device SN74LV157APWR is qualified at MSL1 260C
- Qual Device SN74LV161APWR is qualified at MSL1 260C
- Qual Device SN74LV163APWR is qualified at MSL1 260C
- Qual Device SN74LV165APWR is qualified at MSL1 260C
- Qual Device SN74LV165APWRG3 is qualified at MSL1 260C
- Qual Device SN74LV367APWR is qualified at MSL1 260C
- Qual Device SN74LV594APWR is qualified at MSL1 260C
- Qual Device SN74LV595APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TIs external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-024

TI Information
Selective Disclosure

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV164ADR	Qual Device: SN74LV393ADR	QBS Reference: LM2904BQDRQ1	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C	96 Hours	-	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-	-
UHAST	A3	Unbiased HAST	130C	192 Hours	-	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	3/135/0	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	1/45/0

HTOL	B1	Life Test	125C	1000 Hours	-	-	-	3/231/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	1/77/0
HTOL	B1	Life Test	150C	408 Hours	-	-	3/231/0	-	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/4[1,2]	3/2400/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	1/15/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	1/15/0	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	3/30/0	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	1/3/0	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	3/9/0	1/3/0	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	3/18/0	1/6/0	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	-	-	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV164ADR is qualified at MSL1 260C
- Qual Device SN74LV393ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-059

[1]-Precon and ELFR fails due to a defect screenable at production test. 8D available upon request.
[2]-Precon and ELFR fails due to a defect screenable at production test. 8D available upon request.

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV138ADR	Qual Device: SN74LV157ADR	Qual Device: SN74LV165ADR	Qual Device: SN74LV174ADR	Qual Device: SN74LV367ADR	Qual Device: SN74LV595ADR	Qual Device: SN74LV165ADRG4	QBS Reference: LM2904BQDRQ1	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: SN74LV164APWR	QBS Reference: SN74LV164ADR	QBS Reference: SN74LV393ADR	QBS Reference: SN74LV595AQWBQBRQ1
HAST	A2	Biased HAST	130C	96 Hours	-	-	-	-	-	-	-	3/231/0	-	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	3/231/0	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	-	-	3/231/0	-	-	-	-
UHAST	A3	Unbiased HAST	130C	192 Hours	-	-	-	-	-	-	-	3/231/0	-	-	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	-	-	-	-	-	-	3/231/0	-	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	-	-	-	-	3/231/0	-	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	-	-	-	-	3/135/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	3/135/0	-	-	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	-	-	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	-	-	-	-	-	-	-	-	1/77/0
HTOL	B1	Life Test	150C	408 Hours	-	-	-	-	-	-	-	3/231/0	-	-	-	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	-	-	-	3/2400/4[1,2]	3/2400/0	-	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	1/15/0	1/15/0	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	-	-	-	-	1/15/0	1/15/0	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	-	-	-	-	3/30/0	3/30/0	-	-	-	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-	1/3/0	1/3/0	-	-	-	1/3/0	1/3/0	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	-	-	-	-	-	1/3/0	-	-	-	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	-	-	-	-	3/9/0	1/3/0	-	-	-	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	-	3/18/0	1/6/0	-	-	-	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	1/30/0	-	-	1/30/0	1/30/0	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	-	-	-	-	3/90/0	3/90/0	-	-	-	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV138ADR is qualified at MSL1 260C
- Qual Device SN74LV157ADR is qualified at MSL1 260C
- Qual Device SN74LV166ADR is qualified at MSL1 260C
- Qual Device SN74LV174ADR is qualified at MSL1 260C
- Qual Device SN74LV367ADR is qualified at MSL1 260C
- Qual Device SN74LV595ADR is qualified at MSL1 260C
- Qual Device SN74LV166ADRG4 is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2112-060

[1]-Precon and ELFR fails due to a defect screenable at production test. 8D available upon request.
[2]-Precon and ELFR fails due to a defect screenable at production test. 8D available upon request.

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV06APWR	Qual Device: SN74LV05APWR	Qual Device: SN74LV10APWR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: PSN74LV4T125QPWRQ1
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	1/77/0
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	-	1/77/0
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	3/231/0	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	-	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	3/135/0	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	1/45/0
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	3/231/0	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	-	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	3/2400/0	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	-	1/15/0	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	-	3/30/0	-
ESD	E2	ESD CDM	-	500 Volts	-	-	-	1/3/0	1/3/0
ESD	E2	ESD HBM	-	2000 Volts	-	-	-	1/3/0	1/3/0
LU	E4	Latch-Up	Per JESD78	-	-	-	-	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	1/30/0	1/30/0	-	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	-	3/90/0	3/90/0

- QBS: Qual By Similarity
- Qual Device SN74LV06APWR is qualified at MSL1 260C
- Qual Device SN74LV05APWR is qualified at MSL1 260C
- Qual Device SN74LV10APWR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:
Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2212-044

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV06ADR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: PSN74LV4T125QPWRQ1	QBS Reference: OPA4991QDRQ1	QBS Reference: SN74LV14ADR	QBS Reference: SN74LV21ADR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	3/231/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	1/77/0	3/231/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	-	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	1/77/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	2/154/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	-	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	1/45/0	-	-	-
HTSL	A6	High Temperature Storage Life	175C	500 Hours	-	-	-	1/45/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	-	-	-
HTOL	B1	Life Test	150C	408 Hours	-	-	-	1/77/0	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0	-	-	-	-
ESD	E2	ESD CDM	-	1500 Volts	-	-	-	1/3/0	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	1/3/0	1/3/0	-	-	-
ESD	E2	ESD HBM	-	2000 Volts	-	1/3/0	1/3/0	-	-	-
ESD	E2	ESD HBM	-	4000 Volts	-	-	-	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	-	1/6/0	1/6/0	1/6/0	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-	1/30/0	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	3/90/0	3/90/0	3/90/0	-	-

- QBS: Qual By Similarity
- Qual Device SN74LV06ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2212-046

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV06ADR	QBS Reference: SN74HCS174DR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: PSN74LV4T125QPWRQ1	QBS Reference: SN74LV21ADR
HAST	A2	Biased HAST	130C	96 Hours	-	3/231/0	-	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	1/77/0	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	1/77/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	3/231/0	-	-
UHAST	A3	Unbiased HAST	130C	96 Hours	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65/150C	500 Cycles	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	3/231/0	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	1/77/0	-

HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	1/45/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	3/231/0	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	-	1/77/0	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	3/2400/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;	-	-	3/66/0	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB-Free Solder;	-	-	3/66/0	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	-	-
ESD	E2	ESD CDM	-	250 Volts	-	3/9/0	-	-	-
ESD	E2	ESD CDM	-	500 Volts	-	-	1/3/0	1/3/0	-
ESD	E2	ESD HBM	-	2000 Volts	-	-	1/3/0	1/3/0	-
LU	E4	Latch-Up	Per JESD78	-	-	-	1/6/0	1/6/0	-
CHAR	E5	Electrical Characterization	Min, Typ, Max Temp	-	1/30/0	3/90/0	-	-	1/30/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	3/90/0	-	-	1/30/0
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	-	3/90/0	3/90/0	-

- QBS: Qual By Similarity
- Qual Device SN74LV06ADR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2212-047

Qualification Report
Approve Date 17-MARCH -2023

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name	Condition	Duration	Qual Device: SN74LV06ANSR	QBS Reference: SN74HCS74QPWRQ1	QBS Reference: PSN74LV4T125QPWRQ1	QBS Reference: SN74LV14ANSR	QBS Reference: SN74LVC8T245NSR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	1/77/0	-	-
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0	-	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	-	1/77/0	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	-	1/77/0	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	-	1/77/0	3/231/0
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	3/231/0	-	-	-
TC	A4	Temperature Cycle	-65C/150C	500 Cycles	-	-	1/77/0	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	-	-	3/231/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	3/135/0	-	-	-
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	1/45/0	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	3/231/0	-	-	-
HTOL	B1	Life Test	150C	300 Hours	-	-	1/77/0	-	-
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	3/2400/0	-	-	-
WBS	C1	Ball Shear	76 balls, 3 units min	Wires	-	-	-	1/76/0	-
WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	-	-	1/76/0	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	1/15/0	-	-	-
PD	C4	Physical Dimensions	Cpk>1.67	-	-	3/30/0	-	-	-
ESD	E2	ESD CDM	-	250 Volts	-	-	-	1/3/0	-
ESD	E2	ESD CDM	-	500 Volts	-	1/3/0	1/3/0	-	-
ESD	E2	ESD HBM	-	2000 Volts	-	1/3/0	1/3/0	-	-
LU	E4	Latch-Up	Per JESD78	-	-	1/6/0	1/6/0	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	1/30/0	-
CHAR	E5	Electrical Distributions	Cpk>1.67 Room, hot, and cold	-	-	3/90/0	3/90/0	-	-

- QBS: Qual By Similarity
- Qual Device SN74LV06ANSR is qualified at MSL1 260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-NPD-2212-048

For questions regarding this notice, e-mails can be sent to the contacts shown below or your local Field Sales Representative.

Location	E-Mail
WW Change Management Team	PCN_ww_admin_team@list.ti.com